

5V 128K X 8 CMOS SRAM (Center power and ground)

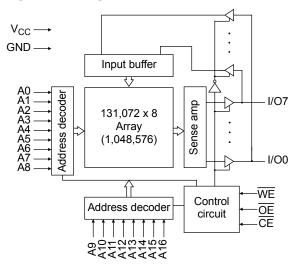
Features

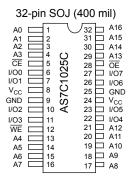
- Industrial (-40° to 85°C) temperature.
- Organization: 131,072 x 8 bits
- High speed
 - 15 ns address access time
 - 6 ns output enable access time
- Low power consumption via chip deselect
- Easy memory expansion with \overline{CE} , \overline{OE} inputs
- Center power and ground
- TTL/LVTTL-compatible, three-state I/O

- JEDEC-standard package
 - 32-pin, 400 mil SOJ
- ESD protection \geq 2000 volts

Pin arrangement

Logic block diagram







Functional description

The AS7C1025C is a 5V high-performance CMOS 1,048,576-bit Static Random Access Memory (SRAM) devices organized as 131,072 x 8 bits. They are designed for memory applications where fast data access, low power, and simple interfacing are desired.

Equal address access and cycle times (t_{AA}, t_{RC}, t_{WC}) of 15 ns with output enable access times (t_{OE}) of 6 ns are ideal for high-performance applications. The chip enable input CE permits easy memory and expansion with multiple-bank memory systems.

When \overline{CE} is high, the device enters standby mode. If inputs are still toggling, the device will consume I_{SB} power. If the bus is static, then full standby power is reached (I_{SB1}).

A write cycle is accomplished by asserting write enable (\overline{WE}) and chip enable (\overline{CE}) . Data on the input pins I/O0 through I/O7 is written on the rising edge of \overline{WE} (write cycle 1) or \overline{CE} (write cycle 2). To avoid bus contention, external devices should drive I/O pins only after outputs have been disabled with output enable (\overline{OE}) or write enable (\overline{WE}) .

A read cycle is accomplished by asserting output enable (\overline{OE}) and chip enable (\overline{CE}) , with write enable (\overline{WE}) high. The chips drive I/O pins with the data word referenced by the input address. When either chip enable or output enable is inactive or write enable is active, output drivers stay in high-impedance mode.

All chip inputs and outputs are TTL-compatible, and operation is from a single 5 V supply. The AS7C1025C is packaged in common industry standard packages.

Absolute maximum ratings

Parameter	Symbol	Min	Max	Unit
Voltage on V _{CC} relative to GND	V _{t1}	-0.50	+7.0	V
Voltage on any pin relative to GND	V _{t2}	-0.50	$V_{CC} + 0.5$	V
Power dissipation	P_{D}	_	1.25	W
Storage temperature (plastic)	T _{stg}	-55	+125	°C
Ambient temperature with V _{CC} applied	T _{bias}	-55	+125	°C
DC current into outputs (low)	I _{OUT}	_	50	mA

Note:

Stresses greater than those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Truth table

CE	WE	OE	Data	Mode
Н	X	X	High Z	Standby (I _{SB} , I _{SB1})
L	Н	Н	High Z	Output disable (I _{CC})
L	Н	L	D_{OUT}	Read (I _{CC})
L	L	X	D_{IN}	Write (I _{CC})

Key: X = don't care, L = low, H = high.



Recommended operating conditions

Parameter	Symbol	Min	Nominal	Max	Unit
Supply voltage	V _{CC}	4.5	5.0	5.5	V
Input voltage	V _{IH}	2.2	_	$V_{CC} + 0.5$	V
input voitage	V _{IL}	-0.5	_	0.8	V
Ambient operating temperature (Industrial)	T _A	-40	_	85	° C

Notes:

 $V_{IL} \min$ = -1.0V for pulse width less than 5ns, once per cycle.

DC operating characteristics (over the operating range) I

			AS7C10	AS7C1025C-15	
Parameter	Symbol	Test conditions	Min	Max	Unit
Input leakage current	I _{LI}	$V_{CC} = Max$, $V_{IN} = GND$ to V_{CC}	-	5	μA
Output leakage current	I _{LO}	$V_{CC} = Max, \overline{CE} = V_{IH},$ $V_{out} = GND \text{ to } V_{CC}$	-	5	μA
Operating power supply current	I_{CC}		-	160	mA
Standby power supply current ¹	I_{SB}	$V_{CC} = Max$ $\overline{CE} ? V_{IH}, f = f_{Max}$	_	40	mA
	I_{SB1}	$ \begin{aligned} &V_{CC} = Max \\ &\overline{CE} ? \ V_{CC} - 0.2 \ V, \\ &V_{IN} ? \ 0.2 \ V \ or \ V_{IN} ? \ V_{CC} - 0.2 \ V, \\ &f = 0 \end{aligned} $		10	mA
Output voltage	V _{OL}	$I_{OL} = 8 \text{ mA}, V_{CC} = \text{Min}$	_	0.4	V
Output voltage	V _{OH}	$I_{OH} = -4 \text{ mA}, V_{CC} = \text{Min}$	2.4	-	V

Capacitance (f = 1 MHz, $T_a = 25^{\circ}$ C, $V_{CC} = NOMINAL)^2$

Parameter	Symbol	Signals	Test conditions	Max	Unit
Input capacitance	C_{IN}	$A, \overline{CE}, \overline{WE}, \overline{OE}$	$V_{IN} = 3dV$	8	pF
I/O capacitance	C _{I/O}	I/O	$V_{IN} = V_{OUT} = 3dV$	8	pF

Note:

This parameter is guaranteed by device characterization, but is not production tested.

 V_{IH} max = V_{CC} +2.0V for pulse width less than 5ns, once per cycle.



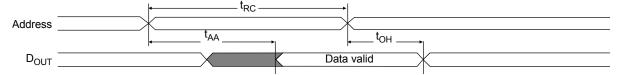
Read cycle (over the operating range)^{3,9}

		AS7C1025C-15			
Parameter	Symbol	Min	Max	Unit	Notes
Read cycle time	t _{RC}	15	_	ns	
Address access time	t _{AA}	_	15	ns	3
Chip enable (CE) access time	t _{ACE}	_	15	ns	3
Output enable (OE) access time	t _{OE}	_	6	ns	
Output hold from address change	t _{OH}	4	_	ns	5
CE low to output in low Z	t _{CLZ}	3	_	ns	4, 5
TE low to output in high Z	t _{CHZ}	0	6	ns	4, 5
OE low to output in low Z	t _{OLZ}	0	_	ns	4, 5
OE high to output in high Z	t _{OHZ}	0	5	ns	4, 5
Power up time	t _{PU}	0	_	ns	4, 5
Power down time	t _{PD}	_	12	ns	4, 5

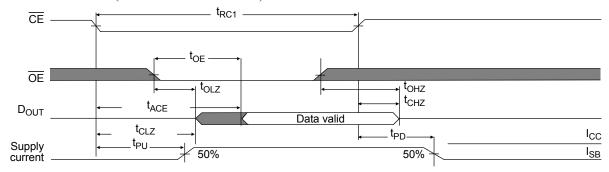
Key to switching waveforms



Read waveform 1 (address controlled)^{3,6,7,9}



Read waveform 2 (CE and OE controlled)^{3,6,8,9}

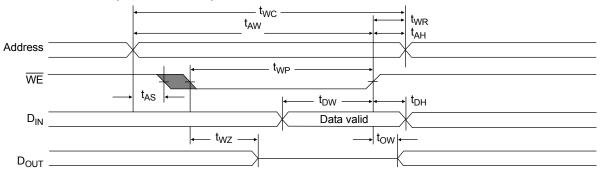




Write cycle (over the operating range) II

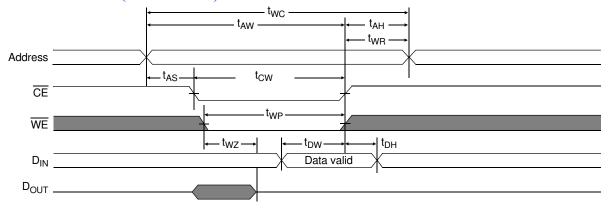
		AS7C1	025C-15		
Parameter	Symbol	Min	Max	Unit	Notes
Write cycle time	t _{WC}	15	_	ns	
Chip enable (\overline{CE}) to write end	t _{CW}	8	_	ns	
Address setup to write end	t _{AW}	8	_	ns	
Address setup time	t _{AS}	0	_	ns	
Write pulse width	t _{WP}	8	_	ns	
Write recovery time	t _{WR}	0	_	ns	
Address hold from end of write	t _{AH}	0	_	ns	
Data valid to write end	t _{DW}	6	_	ns	
Data hold time	t _{DH}	0	_	ns	4, 5
Write enable to output in high Z	t _{WZ}	_	5	ns	4, 5
Output active from write end	t _{OW}	3	_	ns	4, 5

Write waveform 1 ($\overline{\text{WE}}$ controlled)^{10,11}



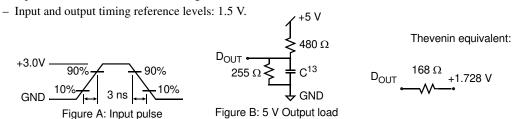


Write waveform 2 (CE controlled)^{10,11}



AC test conditions

- Output load: see Figure B.
- Input pulse level: GND to 30 V. See Figure A.
- Input rise and fall times: 3 ns. See Figure A.

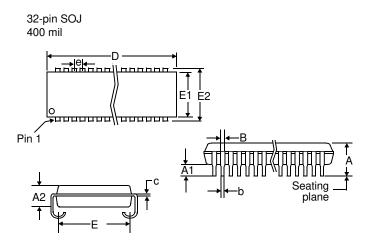


Notes:

- 1 During V_{CC} power-up, a pull-up resistor to V_{CC} on \overline{CE} is required to meet I_{SB} specification.
- 2 This parameter is sampled, but not 100% tested.
- 3 For test conditions, see AC Test Conditions, Figures A and B.
- t_{CLZ} and t_{CHZ} are specified with CL = 5 pF, as in Figure B. Transition is measured ± 200 mV from steady-state voltage.
- 5 This parameter is guaranteed, but not 100% tested.
- $\overline{\text{WE}}$ is high for read cycle.
- 7 $\overline{\text{CE}}$ and $\overline{\text{OE}}$ are low for read cycle.
- 8 Address is valid prior to or coincident with $\overline{\text{CE}}$ transition low.
- 9 All read cycle timings are referenced from the last valid address to the first transitioning address.
- 10 N/A
- 11 All write cycle timings are referenced from the last valid address to the first transitioning address.
- 12 N/A.
- 13 C = 30 pF, except all high Z and low Z parameters where C = 5 pF.



Package dimensions



	32-pin SOJ 400 mil				
Symbol	Min	Max			
A	0.132	0.146			
A1	0.025	-			
A2	0.105	0.115			
В	0.026	0.032			
b	0.015	0.020			
c	0.007	0.013			
D	0.820	0.830			
E	0.354	0.378			
E1	0.395	0.405			
E2	0.435	0.445			
e	0.050 BSC				

Note: This part is compatible with both pin numbering conventions used by various manufacturers.



Ordering Codes

Package	Volt/Temp	15 ns
Plastic SOJ, 400 mil	5V industrial	AS7C1025C-15JIN

Part numbering system

AS7C	1025C	-XX	X	X	X
SRAM prefix	Device number	Access time	Package: J = SOJ 400 mil	Temperature range I = industrial, -40° C to 85° C	N = LEAD FREE PART





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